## Notice of References Cited Application/Control No. 10/797,153 Examiner Kang Hu Applicant(s)/Patent Under Reexamination PARK ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A,	US-2001/0039204 a1	11-2001	Tanskanen, Erkki	463/17
*	В	US-2002/0151344 a1	10-2002	Tanskanen, Erkki	463/17
*	C	US-2004/0039655 a1	02-2004	Chau et al.	705/26
*	D	US-2003/0065805 a1	04-2003	Barnes, Melvin L. JR.	709/231
*	E	US-2003/0220835 a1	11-2003	Barnes, Melvin L. JR.	705/14
*	F	US-2006/0173781 a1	08-2006	Donner, Irah H.	705/050
*	G	US-2006/0173790 a1	08-2006	Park et al.	705/064
	Н	US-			
	ı	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*	,	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004062303 A	02-2004	Japan	MIYAMOTO et al.	none
	0	WO02/01417A2	01-2002	wo	La Brie	none
	P.					
	Q		•			
	R					
	s	•				
	Т			_		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.